

## 測試報告

## Test Report

號碼(No.) : CE/2018/35784

日期(Date) : 2018/03/29

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盛群半導體股份有限公司

HOLTEK SEMICONDUCTOR INC.

新竹市科學工業園區研新二路3號

NO. 3, CREATION RD. II, SCIENCE PARK, HSINCHU 300, TAIWAN, R. O. C.



以下測試樣品係由申請廠商所提供及確認 (The following sample(s) was/were submitted and identified by/on behalf of the applicant as) :

送樣廠商(Sample Submitted By) : 盛群半導體股份有限公司 (HOLTEK SEMICONDUCTOR INC.)  
樣品名稱(Sample Description) : BCM-7602-G01 MODULES  
樣品型號(Style/Item No.) : BCM-7601-G01  
收件日期(Sample Receiving Date) : 2018/03/22  
測試期間(Testing Period) : 2018/03/22 TO 2018/03/29

測試結果(Test Results) : 請參閱下一頁 (Please refer to following pages).

  
Troy Chang, Manager - Tech  
Signed for and on behalf of  
SGS TAIWAN LTD.  
Chemical Laboratory - Taipei



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NO. 3, CREATION RD. II, SCIENCE PARK, HSINCHU 300, TAIWAN, R. O. C.



## 測試結果(Test Results)

測試部位(PART NAME)No. 1 : 整體混測 (MIXED ALL PARTS)

測試項目 (Test Items)	單位 (Unit)	測試方法 (Method)	方法偵測 極限值 (MDL)	結果 (Result)
				No. 1
鎘 / Cadmium (Cd)	mg/kg	參考IEC 62321-5 (2013), 以感應耦合電漿原子發射光譜儀檢測. / With reference to IEC 62321-5 (2013) and performed by ICP-AES.	2	n. d.
鉛 / Lead (Pb)	mg/kg	參考IEC 62321-5 (2013), 以感應耦合電漿原子發射光譜儀檢測. / With reference to IEC 62321-5 (2013) and performed by ICP-AES.	2	n. d.
汞 / Mercury (Hg)	mg/kg	參考IEC 62321-4 (2013), 以感應耦合電漿原子發射光譜儀檢測. / With reference to IEC 62321-4 (2013) and performed by ICP-AES.	2	n. d.
六價鉻 / Hexavalent Chromium Cr(VI)	mg/kg	參考IEC 62321-7-2 (2017), 以UV-VIS檢測. / With reference to IEC 62321-7-2 (2017) and performed by UV-VIS.	8	n. d.
全氟辛烷磺酸 / Perfluorooctane sulfonates (PFOS-Acid, Metal Salt, Amide)	mg/kg	參考US EPA 3550C (2007), 以液相層析/質譜儀檢測. / With reference to US EPA 3550C (2007). Analysis was performed by LC/MS.	10	n. d.
全氟辛酸 / PFOA (CAS No. : 335-67-1)	mg/kg	參考US EPA 3550C (2007), 以液相層析/質譜儀檢測. / With reference to US EPA 3550C (2007). Analysis was performed by LC/MS.	10	n. d.
銻 / Antimony (Sb)	mg/kg	參考US EPA 3050B (1996), 以感應耦合電漿原子發射光譜儀檢測. / With reference to US EPA 3050B (1996). Analysis was performed by ICP-AES.	2	n. d.

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新竹市科學工業園區研新二路3號

NO. 3, CREATION RD. II, SCIENCE PARK, HSINCHU 300, TAIWAN, R. O. C.



測試項目 (Test Items)	單位 (Unit)	測試方法 (Method)	方法偵測 極限值 (MDL)	結果 (Result)
				No. 1
多溴聯苯總和 / Sum of PBBs	mg/kg	參考IEC 62321-6 (2015), 以氣相層析/ 質譜儀檢測. / With reference to IEC 62321-6 (2015) and performed by GC/MS.	-	n. d.
一溴聯苯 / Monobromobiphenyl	mg/kg		5	n. d.
二溴聯苯 / Dibromobiphenyl	mg/kg		5	n. d.
三溴聯苯 / Tribromobiphenyl	mg/kg		5	n. d.
四溴聯苯 / Tetrabromobiphenyl	mg/kg		5	n. d.
五溴聯苯 / Pentabromobiphenyl	mg/kg		5	n. d.
六溴聯苯 / Hexabromobiphenyl	mg/kg		5	n. d.
七溴聯苯 / Heptabromobiphenyl	mg/kg		5	n. d.
八溴聯苯 / Octabromobiphenyl	mg/kg		5	n. d.
九溴聯苯 / Nonabromobiphenyl	mg/kg		5	n. d.
十溴聯苯 / Decabromobiphenyl	mg/kg		5	n. d.
多溴聯苯醚總和 / Sum of PBDEs	mg/kg		-	n. d.
一溴聯苯醚 / Monobromodiphenyl ether	mg/kg		5	n. d.
二溴聯苯醚 / Dibromodiphenyl ether	mg/kg		5	n. d.
三溴聯苯醚 / Tribromodiphenyl ether	mg/kg		5	n. d.
四溴聯苯醚 / Tetrabromodiphenyl ether	mg/kg		5	n. d.
五溴聯苯醚 / Pentabromodiphenyl ether	mg/kg		5	n. d.
六溴聯苯醚 / Hexabromodiphenyl ether	mg/kg		5	n. d.
七溴聯苯醚 / Heptabromodiphenyl ether	mg/kg		5	n. d.
八溴聯苯醚 / Octabromodiphenyl ether	mg/kg		5	n. d.
九溴聯苯醚 / Nonabromodiphenyl ether	mg/kg	5	n. d.	
十溴聯苯醚 / Decabromodiphenyl ether	mg/kg	5	n. d.	
鹵素 (氯) / Halogen-Chlorine (Cl) (CAS No. : 22537-15-1)	mg/kg	參考BS EN 14582 (2016), 以離子層析儀 分析. / With reference to BS EN 14582 (2016). Analysis was performed by IC.	50	300
鹵素 (溴) / Halogen-Bromine (Br) (CAS No. : 10097-32-2)	mg/kg	參考BS EN 14582 (2016), 以離子層析儀 分析. / With reference to BS EN 14582 (2016). Analysis was performed by IC.	50	43100

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新竹市科學工業園區研新二路3號

NO. 3, CREATION RD. II, SCIENCE PARK, HSINCHU 300, TAIWAN, R. O. C.



測試項目 (Test Items)	單位 (Unit)	測試方法 (Method)	方法偵測 極限值 (MDL)	結果 (Result)
				No. 1
鄰苯二甲酸丁苯甲酯 / BBP (Butyl Benzyl phthalate) (CAS No. : 85-68-7)	mg/kg	參考IEC 62321-8 (2017), 以氣相層析儀 / 質譜儀檢測. / With reference to IEC 62321-8 (2017). Analysis was performed by GC/MS.	50	n. d.
鄰苯二甲酸二丁酯 / DBP (Dibutyl phthalate) (CAS No. : 84-74-2)	mg/kg		50	n. d.
鄰苯二甲酸二異丁酯 / DIBP (Di-isobutyl phthalate) (CAS No. : 84-69-5)	mg/kg		50	n. d.
鄰苯二甲酸二(2-乙基己基)酯 / DEHP (Di-(2-ethylhexyl) phthalate) (CAS No. : 117-81-7)	mg/kg		50	n. d.

**備註(Note) :**

1. mg/kg = ppm ; 0.1wt% = 1000ppm
2. n. d. = Not Detected (未檢出)
3. MDL = Method Detection Limit (方法偵測極限值)
4. "-" = Not Regulated (無規格值)
5. 樣品的測試是基於申請人要求混合測試，報告中的混合測試結果不代表其中個別單一材質的含量。(The samples was/were analyzed on behalf of the applicant as mixing sample in one testing. The above results was/were only given as the informality value.)

**PFOS參考資訊(Reference Information) : 持久性有機污染物 POPs - (EU) 757/2010**

PFOS濃度在物質或製備中不得超過0.001%(10ppm)，在半成品、成品或零部件中不得超過0.1%(1000ppm)，在紡織品或塗層材料中不得超過1µg/m<sup>2</sup>。

(Outlawing PFOS as substances or preparations in concentrations above 0.001% (10ppm), in semi-finished products or articles or parts at a level above 0.1%(1000ppm), in textiles or other coated materials above 1µg/m<sup>2</sup>.)

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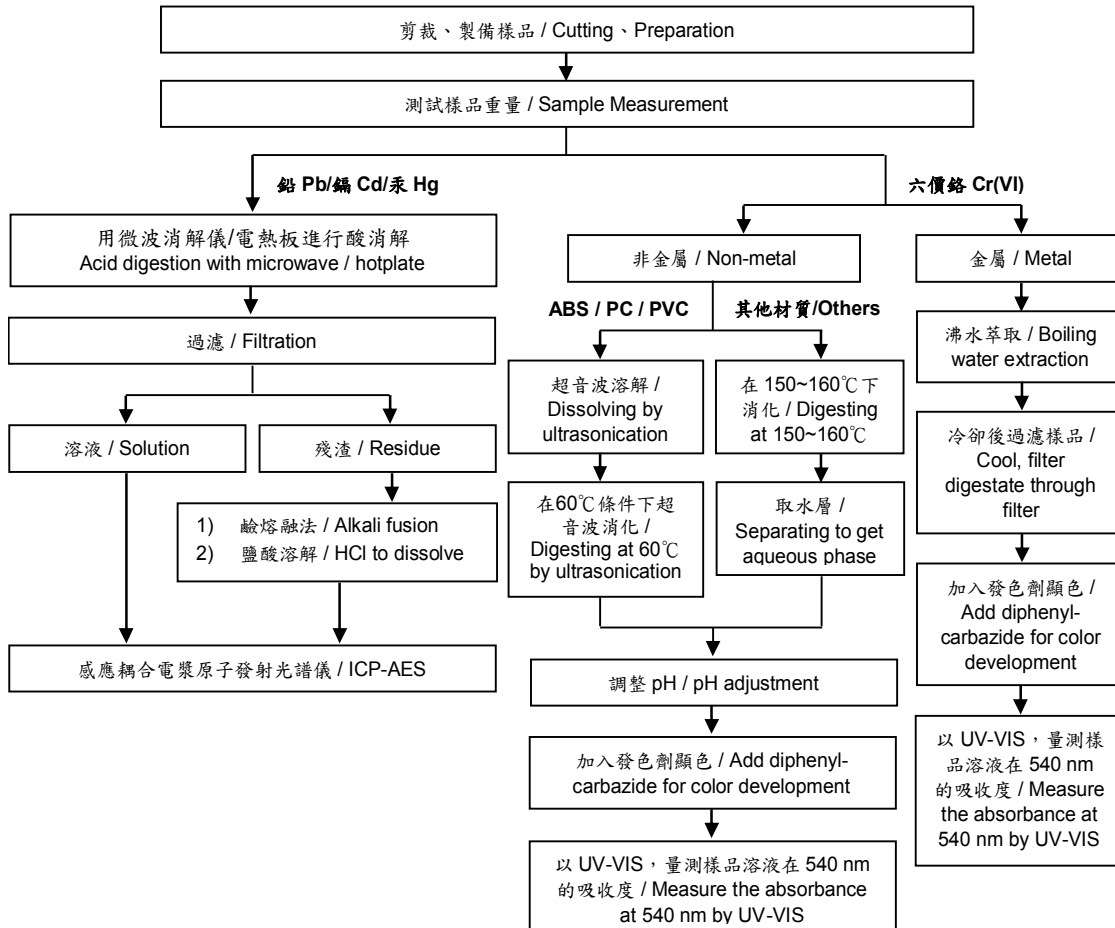


### 重金屬流程圖 / Analytical flow chart of Heavy Metal

根據以下的流程圖之條件，樣品已完全溶解。(六價鉻測試方法除外)

These samples were dissolved totally by pre-conditioning method according to below flow chart. (Cr<sup>6+</sup> test method excluded)

- 測試人員：王志瑋 / Technician : JR Wang
- 測試負責人：張啟興 / Supervisor: Troy Chang



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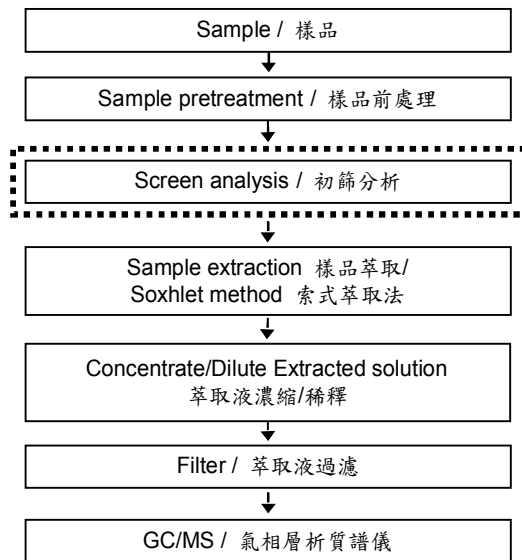
NO. 3, CREATION RD. II, SCIENCE PARK, HSINCHU 300, TAIWAN, R. O. C.



### 多溴聯苯/多溴聯苯醚分析流程圖 / Analytical flow chart - PBB/PBDE

- 測試人員：涂雅苓 / Technician: Yaling Tu
- 測試負責人：張啟興 / Supervisor: Troy Chang

初次測試程序 / First testing process —————>  
 選擇性篩檢程序 / Optional screen process .....  
 確認程序 / Confirmation process - . - .>



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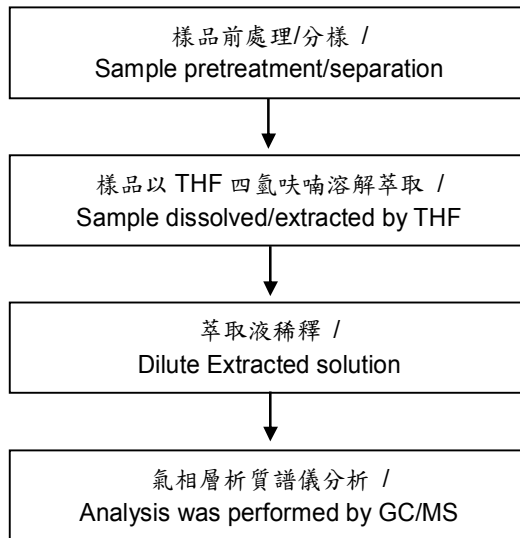
NO. 3, CREATION RD. II, SCIENCE PARK, HSINCHU 300, TAIWAN, R. O. C.



### 可塑劑分析流程圖 / Analytical flow chart - Phthalate

- 測試人員：徐毓明 / Technician: Andy Hsu
- 測試負責人：張啟興 / Supervisor : Troy Chang

#### **【測試方法/Test method: IEC 62321-8】**



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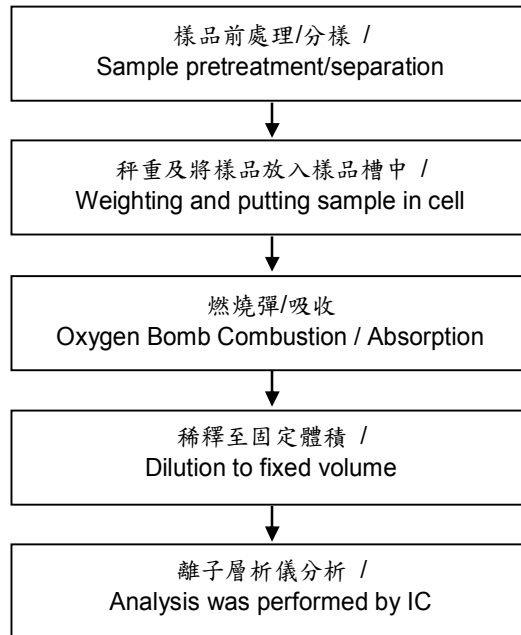
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NO. 3, CREATION RD. II, SCIENCE PARK, HSINCHU 300, TAIWAN, R. O. C.



### 鹵素分析流程圖 / Analytical flow chart - Halogen

- 測試人員：陳恩臻 / Technician: Rita Chen
- 測試負責人：張啟興 / Supervisor: Troy Chang



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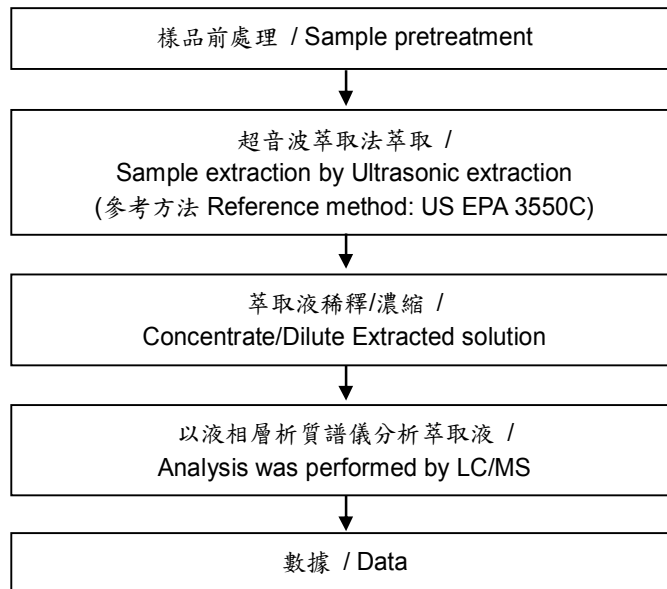
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NO. 3, CREATION RD. II, SCIENCE PARK, HSINCHU 300, TAIWAN, R. O. C.



### 全氟辛酸/全氟辛烷磺酸分析流程圖 / Analytical flow chart - PFOA/PFOS

- 測試人員：涂雅苓 / Technician: Yaling Tu
- 測試負責人：張啟興 / Supervisor: Troy Chang



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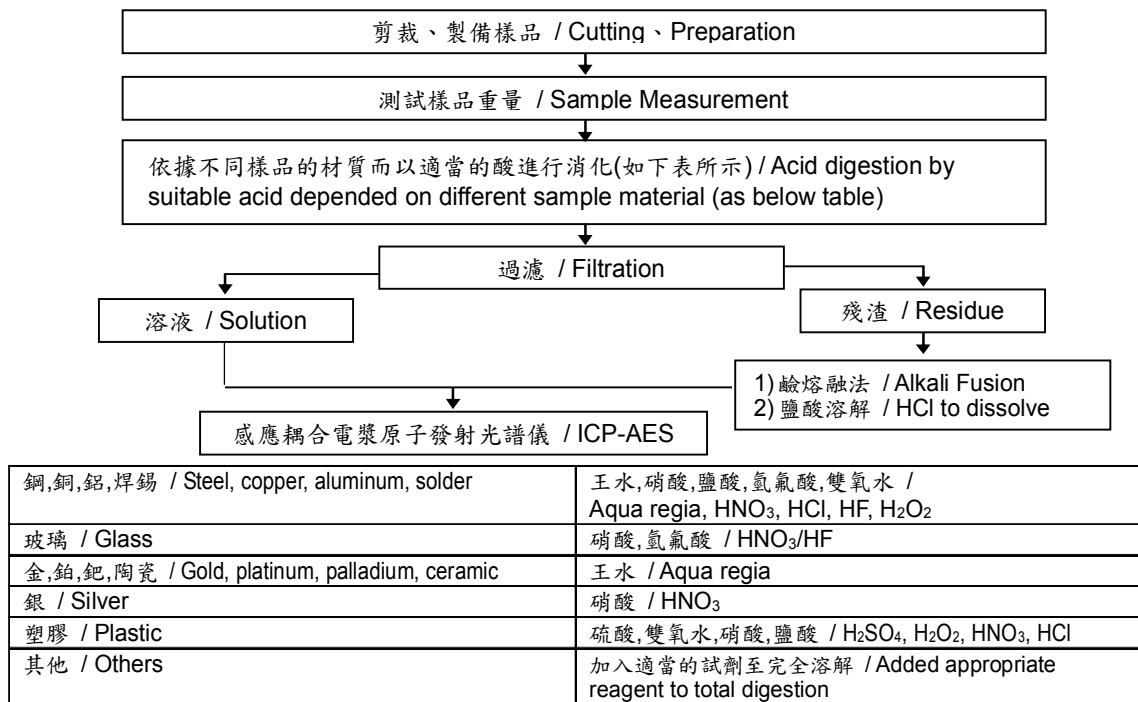
NO. 3, CREATION RD. II, SCIENCE PARK, HSINCHU 300, TAIWAN, R. O. C.



根據以下的流程圖之條件，樣品已完全溶解。 / These samples were dissolved totally by pre-conditioning method according to below flow chart.

- 測試人員：陳恩臻 / Technician: Rita Chen
- 測試負責人：張啟興 / Supervisor: Troy Chang

元素以 ICP-AES 分析的消化流程圖  
(Flow Chart of digestion for the elements analysis performed by ICP-AES)



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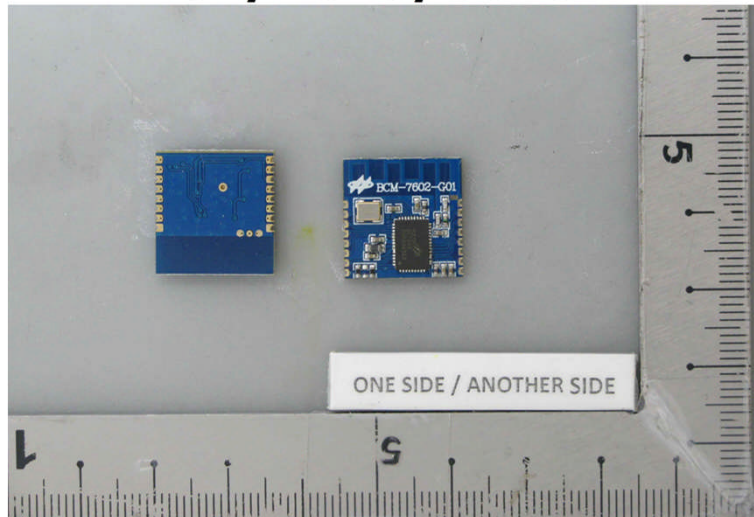
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\* 照片中如有箭頭標示，則表示為實際檢測之樣品/部位。 \*  
(The tested sample / part is marked by an arrow if it's shown on the photo.)

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\*\* 報告結尾 (End of Report) \*\*